Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/670,792	NAGANO ET AL.
Examiner	Art Unit
Jim Vannucci	2828

SEARCHED				
Class	Subclass	Date	Examiner	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u> </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
block, step, array, lens, 372/10, ofset, staggered	9/15/2005	٦V	